Notice of References Cited

		~			
_	Application/Control No.		Applicant(s)/Patent Under Reexamination		
	09/809,488	,	Reexamination HIRANO ET A		
	Examiner		Art Unit		
	Binh-An D. Nguyen		3713	Page 1 of 2	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name		ication :
	Α	US-4615093	10-1986	Tews et al	29	407×.
	В	US-4827436	05-1989	Sabersky et al	364	559x
	С	US-4969256	11-1990	Shimizu et al	29	834x *
	D	US-5086556	02-1992	Toi	29	740x
	E	US-5145099	09-1992	Wood et al	228	9x
	F	US-5278634	01-1994	Skunes et al	356	400 ·
	G	US-5384956	01-1995	sakurai et al	29	834x
	Н	US-5498942	03-1996	Ijuin	318	567x
	ı	US-5568264	10-1996	Nakatsuka et al	356	394x*
	J	US-5570993	11-1996	Onodera et al	414	783x
	κ	US-5588195	12-1996	Asai et al	29	33M x
	L	US-5607097	03-1997	Sato et al	228	8 x
	М	US-5608642	03-1997	Onodera	364	478.01x

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY Country		Name	Classification	
	N				,		
	0						
	Р						٠.,
	a		·				
	R			•			. •
	s						
	Т						

NON-PATENT DOCUMENTS

	NOW-I ATEN DOGGLATO								
*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)								
	U		:						
	V		•						
	w		•						
``	`.x	·* ·							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No. 09/809,488	_	Applicant(s)/Pater Reexamination HIRANO ET AL.	nt Under
Examiner		Art Unit	
Binh-An D. Nguyen		3713	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	l Nomes		fication
	Α	US-5639009	06-1997	Abe	228	102x
	В	US-5660519	08-1997	Ohta et al	414	783x
	С	US-5741114	04-1998	Onodera	414	783x _
	D.	US-5768759	06-1998	Hudson	29	407.04x
	Е	US-5768765	06-1998	Fujioka et al	29	740x
	F	US-5858806	01-1999	Nishida	438	7x
	G	US-5884831	03-1999	Sato et al	228	6.2x
	Н	US-5924192	07-1999	Wuyts	29	833x
	ı	US-6056109	05-2000	Hidai et al	198	431x °
	J	US-6088911	07-2000	Isogai et al	29	740x
	к	US-6230393	05-2001	Hirano et al	29	740x
	L	US-				
	М	US-				

FOREIGN PATENT DOCUMENTS

*			Date MM-YYYY Country		Name	Classification
	N					
	0					
	Р					
.A. p. 194	Q					
	R					
	s					
	Т	, , , , , , , , , , , , , , , , , , , ,				

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		· · · · · · · · · · · · · · · · · · ·
	۷,		
	w		
	х		`

*A copy of this reference is not being furnished with this Office action. (See MPEP, § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.